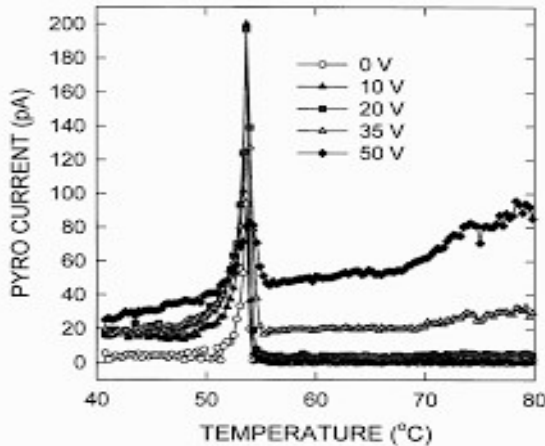


SOLAR TEST SYSTEM



ABOUT THE SYSTEM

Solar test system is designed and developed by our company looking into wide variety of research requirements in the field of non-conventional energy resources and energy harvesting devices. The system uses a advance SMU unit fully interfaced with a test sample holder for wafers. The wafer can be heated with a light source programmed to produce a particular wavelength. Similarly a charging and discharging cycle can also be measured with respect to temperature. The system is designed by our company are most advanced in its specifications and can undertake various tests needed by researchers. The complete system is fully automatic with temperature variation. The system also has option to go beyond room temperature with high temperature options such as 500K, 773K

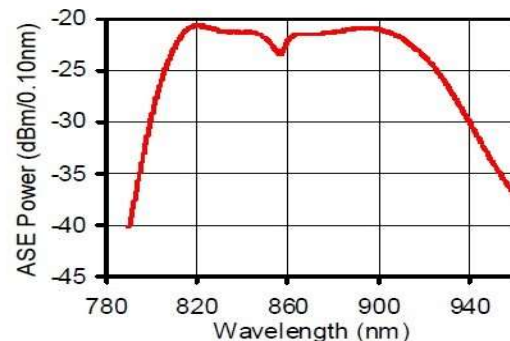
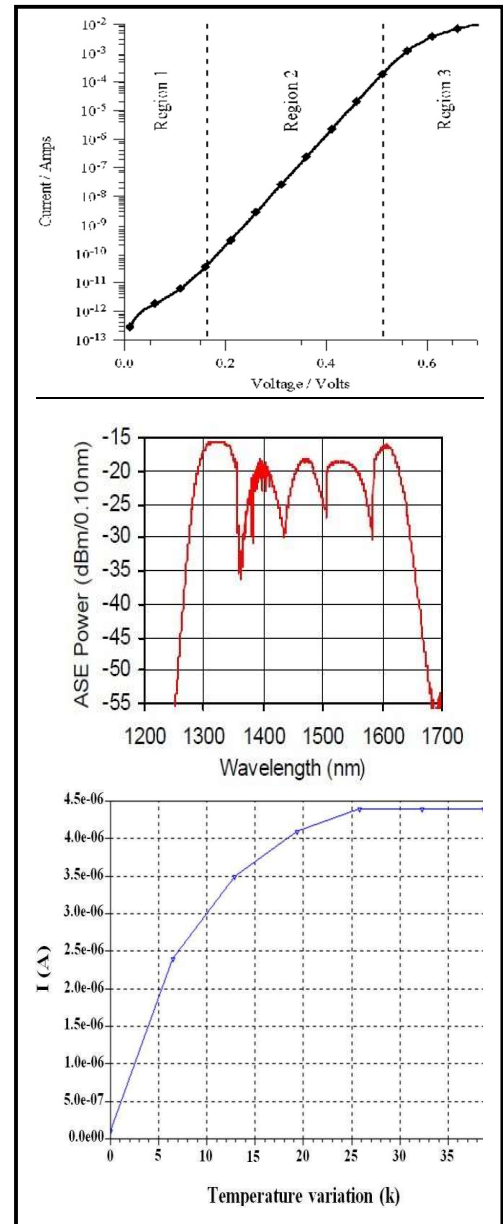
MODEL: SOL42

Various Tests Performed:

- Current vs Temperature
- Power generated at different temperature

Optional Tests Performed:

- Wavelength vs current at different Temp



SOLAR TEST SYSTEM

TECHNICAL SPECIFICATION

The solar test system software performs important functions of the measurement automatically without any human interventions. Following are highlights of important functions:

- Simultaneous measurement of Pyro Current vs Temperature.
- Automatic measurement of Power generated at different temperature
- Representation of data and graphs in automatic scale.
- Online math work for different calculations using sample dimensions to calculate pyro parameters.
- Data in standard ASCII Format exportable to standard software's like excel origin etc.

| | |
|--|---------------------------|
| Solar Test system | 6500b |
| Current Range | 2nA–20mA |
| Resolution | 10fA |
| Voltage Burden | 200µV (1mV on 20mA range) |
| Reading Rate | 1000/s |
| Digits | 5½ |
| Analog Output | Yes |
| Battery Option | No |
| Temperature Options | Model |
| Microprobe Temperature Stage | RT250 (RT – 500K) |
| High Temperature Stage I | RT500 (RT – 773K) |
| High Temperature Stage II | RT800 (RT – 1073K) |
| Test Specimen | Two/Four Probe |
| Sample Dimension | 50X50 mm |
| Thickness (Bulk) | 0.1mm to 1mm |
| Thickness (Film) | 10µm to 100µm |
| Wide Band Light Source | Specification |
| Wavelength Range (nm) | 930 to 1100 |
| Center Wavelength (nm) | 1000 |
| 3-dB Bandwidth (nm) | 105 |
| Total Output Power (mW) | 4 |
| Wide Band Light Source option is only available in temp option - RT250 (RT – 500K) & RT500 (RT – 773K) | |
| *For detailed specification, please refer to respective brochures. | |
| Also, the microprobe station is for thin film measurement | |

MARINE INDIA

Regd Off – A-3/25B Green Apartment Paschim Vihar New Delhi – 110063, INDIA
Off Works – 7/23 2nd Floor Kirti Nagar Industrial Area New Delhi – 110015, INDIA

Ph/Fax: +91 – 11- 41428187, +91 – 9810289961

Email: sales@marineindia.com, info@marineindia.com

www.marineindia.com